

N-Channel 500V (D-S)Power MOSFET

PRODUCT SUMMARY				
V _{DS} (V)	500			
$R_{DS(on)}(\Omega)$	V _{GS} = 10 V	0.660		
Q _g (Max.) (nC)	81			
Q _{gs} (nC)	20			
Q _{gd} (nC)	36			
Configuration	Single			

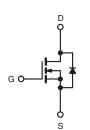
FEATURES

 $\bullet\,$ Lower Gate Charge Q_g Results in Simpler Drive



- Improved Gate, Avalanche and Dynamic dV/dt Ruggedness
- Fully Characterized Capacitance and Avalanche Voltage
- Compliant to RoHS Directive 2002/95/EC





N-Channel MOSFET

ABSOLUTE MAXIMUM RATINGS (T _C = 25 °C, unless otherwise noted)							
PARAMETER			SYMBOL	LIMIT	UNIT		
Drain-Source Voltage			V _{DS}	500	V		
Gate-Source Voltage			V _{GS}	± 20			
Continuous Drain Current	V at 10 V	T _C = 25 °C	- I _D	13			
Continuous Drain Current	V _{GS} at 10 V	T _C = 100 °C		8.1	Α		
Pulsed Drain Current ^a			I _{DM}	50			
Linear Derating Factor				2.0	W/°C		
Single Pulse Avalanche Energy ^b			E _{AS}	560	mJ		
Avalanche Current ^a			I _{AR}	13	Α		
Repetitive Avalanche Energy ^a			E _{AR}	25	mJ		
Maximum Power Dissipation	T _C = 25 °C		T _C = 25 °C		P _D	250	W
Peak Diode Recovery dV/dt ^c			dV/dt	9.2	V/ns		
Operating Junction and Storage Temperature Range		T _J , T _{stg}	- 55 to + 150	°C			
Soldering Recommendations (Peak Temperature)	for	10 s		300 ^d			
Maurina Taraus	6-32 or M3 screw			10	lbf · in		
Mounting Torque				1.1	N · m		

- a. Repetitive rating; pulse width limited by maximum junction temperature (see fig. 11). b. Starting T_J = 25 °C, L = 5.7 mH, R_g = 25 Ω , I_{AS} =14 A, dV/dt = 7.6 V/ns (see fig. 12a). c. I_{SD} \leq 14 A, dI/dt \leq 250 A/µs, V_{DD} \leq V_{DS}, T_J \leq 150 °C.

- d. 1.6 mm from case.



THERMAL RESISTANCE RATINGS					
PARAMETER	SYMBOL	TYP.	MAX.	UNIT	
Maximum Junction-to-Ambient	R _{thJA}	-	62		
Case-to-Sink, Flat, Greasd Surface	R _{thCS}	0.50	-	°C/W	
Maximum Junction-to-Case (Drain)	R _{thJC}	-	0.50		

PARAMETER	SYMBOL	TES	MIN.	TYP.	MAX.	UNIT	
Static							
Drain-Source Breakdown Voltage	V_{DS}	V _{GS}	= 0 V, I _D = 250 μA	500	-	-	V
V _{DS} Temperature Coefficient	$\Delta V_{DS}/T_{J}$	Reference	e to 25 °C, I _D = 1 mA	-	0.55	-	V/°C
Gate-Source Threshold Voltage	V _{GS(th)}	V _{DS} =	$V_{DS} = V_{GS}, I_{D} = 250 \mu\text{A}$		-	4.0	V
Gate-Source Leakage	I _{GSS}		V _{GS} = ± 20V		-	±100	nA
Zana Cata Valtana Duain Commant		V _{DS} =	V _{DS} = 500 V, V _{GS} = 0 V		-	25	μΑ
Zero Gate Voltage Drain Current	I _{DSS}	V _{DS} = 400 \	V _{DS} = 400 V, V _{GS} = 0 V, T _J = 125 °C		-	250	
Drain-Source On-State Resistance	R _{DS(on)}	V _{GS} = 10 V	I _D = 8.4 A ^b	-	0.660	-	Ω
Forward Transconductance	9fs	V _{DS}	V _{DS} = 50 V, I _D = 8.4 A		-	-	S
Dynamic							
Input Capacitance	C _{iss}		$V_{GS} = 0 V$,		1910	-	
Output Capacitance	C _{oss}		$V_{DS} = 25 \text{ V},$	-	290	-	
Reverse Transfer Capacitance	C _{rss}	f = 1	f = 1.0 MHz, see fig. 5		11	-	
0.14.104.44	_		V _{DS} = 1.0 V, f = 1.0 MHz	-	2730	-	- pF -
Output Capacitance	C_{oss}	$V_{GS} = 0 V$	V _{GS} = 0 V V _{DS} = 400 V, f = 1.0 MHz	-	82	-	
Effective Output Capacitance	Coss eff.		V _{DS} = 0 V to 400 V ^c	-	160	-	
Total Gate Charge	Q _g			-	-	81	
Gate-Source Charge	Q _{gs}	$I_D = 14 \text{ A}, V_{DS} = 400 \text{ V},$ see fig. 6 and 13^b		-	-	20	nC
Gate-Drain Charge	Q _{gd}		occ lig. o and ro	-	-	36	
Turn-On Delay Time	t _{d(on)}	V _{GS} = 10 V		-	15	-	
Rise Time	t _r		$V_{DD} = 250 \text{ V}, I_D = 14 \text{ A},$	-	39	-	1
Turn-Off Delay Time	t _{d(off)}		$R_g = 7.5 \Omega$, see fig. 10^b		39	-	ns
Fall Time	t _f			-	31	-	
Drain-Source Body Diode Characteristic	s						
Continuous Source-Drain Diode Current	IS	MOSFET symbol showing the integral reverse p - n junction diode		-	-	13	^
Pulsed Diode Forward Current ^a	I _{SM}			-	-	56	- A
Body Diode Voltage	V _{SD}	T _J = 25 °C, I _S = 14 A, V _{GS} = 0 V ^b		-	-	1.5	V
Body Diode Reverse Recovery Time	t _{rr}	T _J = 25 °C, I _F = 14 A, T _J = 125 °C, dl/dt = 100 A/μs ^b		-	370	550	ns
Body Diode Reverse Recovery Charge	Q_{rr}			-	4.4	6.5	μC
Body Diode Reverse Recovery Current	I _{RRM}			-	21	31	Α
Forward Turn-On Time	t _{on}	Intrinsic tu	ırn-on time is negligible (turn-	on is do	minated b	y L _S and	L _D)

Notes

- a. Repetitive rating; pulse width limited by maximum junction temperature (see fig. 11).
- b. Pulse width $\leq 300~\mu s$; duty cycle $\leq 2~\%$.
- c. C_{oss} eff. is a fixed capacitance that gives the same charging time as C_{oss} while V_{DS} is rising from 0 % to 80 % V_{DS} .



TYPICAL CHARACTERISTICS (25 °C, unless otherwise noted)

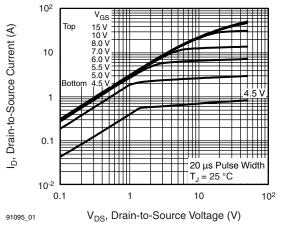


Fig. 1 - Typical Output Characteristics

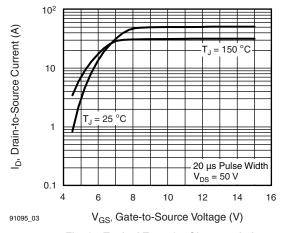


Fig. 3 - Typical Transfer Characteristics

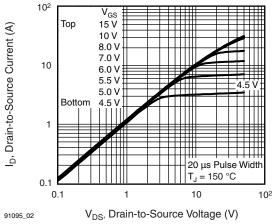


Fig. 2 - Typical Output Characteristics

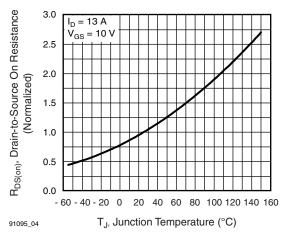


Fig. 4 - Normalized On-Resistance vs. Temperature



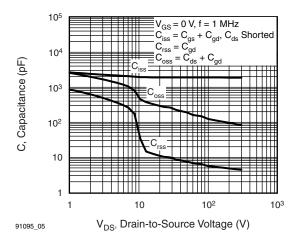


Fig. 5 - Typical Capacitance vs. Drain-to-Source Voltage

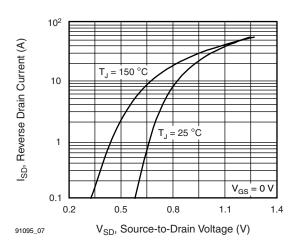


Fig. 7 - Typical Source-Drain Diode Forward Voltage

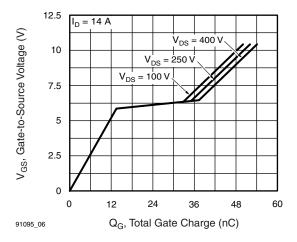


Fig. 6 - Typical Gate Charge vs. Gate-to-Source Voltage

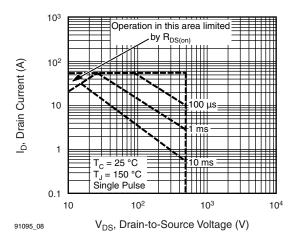


Fig. 8 - Maximum Safe Operating Area



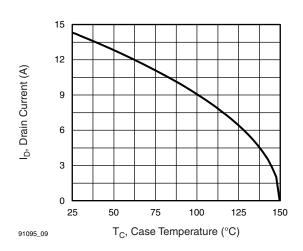


Fig. 9 - Maximum Drain Current vs. Case Temperature

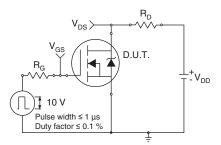


Fig. 10a - Switching Time Test Circuit

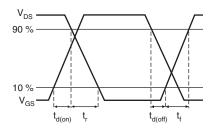


Fig. 10b - Switching Time Waveforms

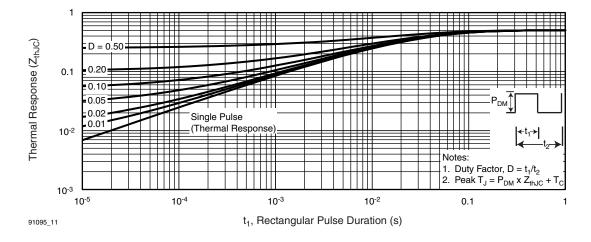
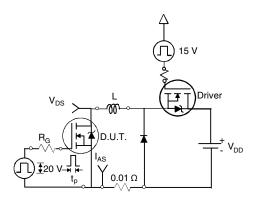
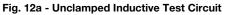


Fig. 11 - Maximum Effective Transient Thermal Impedance, Junction-to-Case







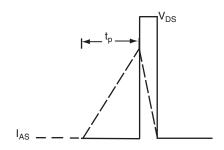


Fig. 12b - Unclamped Inductive Waveforms

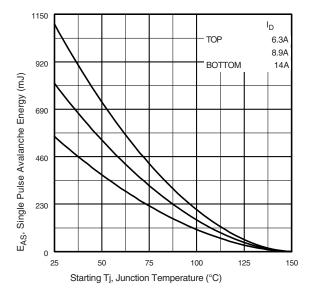


Fig. 12c - Maximum Avalanche Energy vs. Drain Current

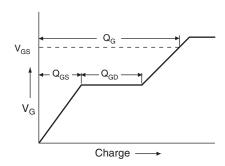


Fig. 13a - Basic Gate Charge Waveform

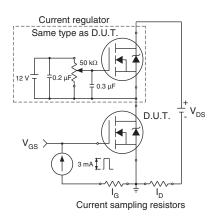
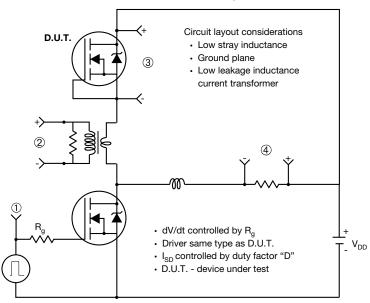


Fig. 13b - Gate Charge Test Circuit



Peak Diode Recovery dV/dt Test Circuit



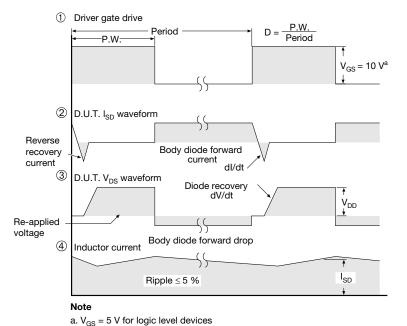
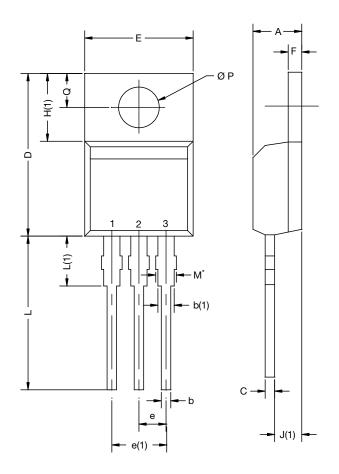


Fig. 14 - For N-Channel



TO-220AB



INC	CHES
MIN.	MAX.
0.167	0.183
0.027	0.040
0.045	0.070
0.014	0.024
0.564	0.624
0.392	0.414
0.095	0.105
0.192	0.208
0.045	0.055
0.240	0.264
0.095	0.115
0.526	0.567
0.131	0.159
0.139	0.155
0.100	0.118

Note

 $\bullet~M^{\star}=0.052$ inches to 0.064 inches (dimension including protrusion), heatsink hole for HVM



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